

REMARKS

Claim 1 is pending in this application. Amendment has been made to the Abstract. No amendment has been made to the claim.

The abstract of the disclosure is objected to (Office action point 1).

The objection is overcome by the Amendment to the abstract. The amended Abstract is a single paragraph.

Claim 1 is rejected under 35 U.S.C. 102(b) as anticipated by Marumo et al. (U.S. Pat. No. 5,525,911) (Office action point 3).

The rejection of claim 1 is respectfully traversed.

The Examiner has taken Marumo's earth plate 22 as the recited main substrate; coaxial probes 31 as the recited probes; fixing blocks 23, 24, 25 and 26 as the recited probe support; guide plate 27 as the recited upper guide plate; fixing block 26 as the recited lower guide plate; and indicates that guide plates 28 and 29 represent the recited plurality of substrates laminated separably.

Applicants respectfully disagree with the Examiner that Marumo discloses the elements recited in claim 1. In particular, the Examiner's assignment requires that Marumo's guide plates 28 and 29 be taken as the recited plurality of substrates laminated separably.

However, it is clear from Marumo's Figs. 1 and 2 that guide plates 28 and 29 are not in contact with each other, and therefore are not "laminated". Column 5, line 35, of Marumo also

indicates that guide plates 28 and 29 are kept separated from one another.

Secondly, it is also clear that Marumo's guide plates 28 and 29 are not arranged "separably". Applicants note that "separably" in the present claim and specification clearly means "removably" and does not mean "separated from each other." Marumo, column 4, lines 49-51, indicates that "The lower fixing block 26 holds two guide plates 28 and 29 at the center thereof." In Marumo's Fig. 1, guide plates 28 and 29 appear to be permanently mounted in block 26. There is no indication that these can be separated (removed) from Marumo's apparatus.

Applicants therefore assert that claim 1 is not anticipated by Marumo et al. (U.S. Pat. No. 5,525,911).

If, for any reason, it is felt that this application is not now in condition for allowance, the Examiner is requested to contact Applicants undersigned Agent at the telephone number indicated below to arrange for an interview to expedite the disposition of this case.

Attached hereto is a marked-up version of the changes made by the current amendment. The attached page is captioned "**Version with markings to show changes made.**"

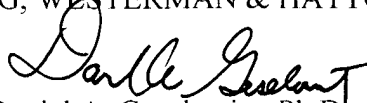
Amendment under 37 CFR 1.111
Masao OKUBO et al.

U.S. Patent Application S.N. 09/851,946
Attorney Docket No. 010609

In the event that this paper is not timely filed, Applicants respectfully petition for an appropriate extension of time. Please charge any fees for such an extension of time and any other fees which may be due with respect to this paper, to Deposit Account No. 01-2340.

Respectfully submitted,

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PATENT TRADEMARK OFFICE

Enclosures: Version with markings to show changes made
Abstract of the Disclosure (1 page)

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VERSION WITH MARKINGS TO SHOW CHANGES MADE

IN THE ABSTRACT:

Please amend the Abstract as follows:

Purpose: To present a vertical probe card capable of reusing without replacing a broken probe if a probe is broken.

Constitution: A vertical probe card having vertical probes 100, being used in measurement of electric characteristics of an LSI chip 610 to be measured, comprising a main substrate 300 forming conductive patterns 310, a plurality of probes 100 drooping vertically from the main substrate 300, and a probe support 200 provided at the back side of the main substrate 300 for supporting the probes 100, in which the probe support 200 is disposed parallel to the main substrate 300, and has an upper guide plate 210 and a lower guide plate 220 for supporting the probes 100 by passing the through-holes 211, 221 opened in each, and the lower guide plate 220 is composed of three substrates 220A, 220B, 220C laminated separably.

~~Selected Drawing: Fig. 2.~~

ABSTRACT OF THE DISCLOSURE

At Purpose: To present a vertical probe card capable of reusing without replacing a broken probe if a probe is broken. Constitution: A vertical probe card having vertical probes 100, being used in measurement of electric characteristics of an LSI chip 610 to be measured, comprising a main substrate 300 forming conductive patterns 310, a plurality of probes 100 drooping vertically from the main substrate 300, and a probe support 200 provided at the back side of the main substrate 300 for supporting the probes 100, in which the probe support 200 is disposed parallel to the main substrate 300, and has an upper guide plate 210 and a lower guide plate 220 for supporting the probes 100 by passing the through-holes 211, 221 opened in each, and the lower guide plate 220 is composed of three substrates 220A, 220B, 220C laminated separably.
